



GAU 2829

IN THE UNITED STATES
PATENT AND TRADEMARK OFFICE

PATENT APPLICATION

INVENTORS:

Yinon Degani
Charlie Chunlei Gao
King Lien Tai

CASE: S1

FIRST CLASS MAIL

These papers are being deposited
as FIRST CLASS MAIL with the
US POST OFFICE addressed to:
COMMISSIONER FOR PATENTS
ARLINGTON, VA 22313-1450
by *[Signature]*
date July 13, 2004

SERIAL NO.: 10/053,818

GROUP ART UNIT: 2829

FILING DATE: 01/22/02

EXAMINER: Nguyen, Vinh P

TITLE: TESTING INTEGRATED CIRCUITS

COMMISSIONER FOR PATENTS
ARLINGTON, VA 22313-1450

In response to the final Office Action mailed 04/13/04 please amend the
above- identified application as follows, and consider the remarks that follow the
amendments.

Please change the title to read:

-- MEMBRANE TEST APPARATUS FOR INTEGRATED
CIRCUIT TESTING --

Please amend the claims as follows: